Erratum to: A Cost-Efficient Self-Configurable BIST Technique for Testing Multiplexer-Based FPGA Interconnect

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Unfortunately the authors' given names and surnames were altered in the original article. The correct authors' names should be as follows (Given name + Surname): Jianfeng Zhu, Hu He, Dong Wu, and Liyang Pan. The error is regretted.

The online version of the original article can be found at <http://dx.doi.org/10.1007/s10836-011-5238-3>.

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